L Number	Hits	Search Text	DB	Time stamp
1	200	wafer and in-line and yield and prediction	USPAT;	2004/09/01 12:18
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
2	16493	wafer and yield and analysis	-USPAT;	2004/09/01 12:19
			US-PGPUB;	
1			EPO; JPO;	
1			DERWENT;	
]			IBM_TDB	
3	2711	(wafer and yield and analysis) and statistical	USPAT;	2004/09/01 12:19
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
4	665	((wafer and yield and analysis) and statistical) and	USPAT;	2004/09/01 12:19
		regression	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	2004/00/04 42 20
5	601	(((wafer and yield and analysis) and statistical) and	USPAT;	2004/09/01 12:20
		regression) and sample	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
	400		IBM_TDB	2004/00/01 12:20
6	409	((((wafer and yield and analysis) and statistical) and	USPAT;	2004/09/01 12:20
		regression) and sample) and parameter	US-PGPUB;	
			EPO; JPO;	
			DERWENT; IBM_TDB	
]	16	702/84.ccls. and database and test and correlation	USPAT;	2004/08/31 13:19
-	10	702/04.Ccis. and database and test and correlation	US-PGPUB;	2007/00/31 13.13
]			EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	9	702/84.ccls. and database and test and analyze and	USPAT;	2004/08/27 09:56
	,	correlation and wafer	US-PGPUB;	200,700,20
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
-	100	700/109.ccls. and wafer	USPAT;	2004/08/31 13:58
			US-PGPUB;	
			EPO; JPO;	
[DERWENT;	
			IBM_TDB	
-	669	wafer and (quality near control) and analyzing	USPAT;	2004/08/31 14:00
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
	. = =		IBM_TDB	2004/00/04 44 40
-	108	(wafer and (quality near control) and analyzing) and	USPAT;	2004/08/31 14:19
		parameter and lot and sample	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
	^	(auglib, adj control) came toot came as section	IBM_TDB	2004/09/21 14:20
_	9	(quality adj control) same test same parameter same	USPAT;	2004/08/31 14:29
		analyzing	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
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-	505	(quality adj control) and sample and parameter and search and database and analyzing	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/08/31 14:31
-	40	((quality adj control) and sample and parameter and search and database and analyzing) and correlating and predicting	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2004/08/31 14:32
	113	((quality adj control) and sample and parameter and search	DERWENT; IBM_TDB USPAT;	2004/08/31 14:37
		and database and analyzing) and correlating	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
-	31	((quality adj control) and sample and parameter and search and database and analyzing) and (((quality adj control) and sample and parameter and search and database and analyzing) and correlating) and wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/31 15:15